February 2001

## FDS3890

## 80V N-Channel Dual PowerTrench<sup>®</sup> MOSFET

### **General Description**

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This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

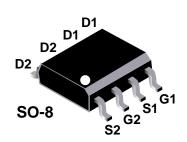
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable  $R_{_{\text{DS(ON)}}}$  specifications. The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

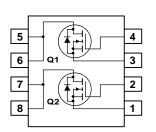
### Features

4.7 A, 80 V.

$$R_{DS(ON)} = 44 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$$
  
 $R_{DS(ON)} = 50 \text{ m}\Omega @ V_{GS} = 6 \text{ V}$ 

- Fast switching speed
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Unit
V <sub>DSS</sub>	Drain-Source Voltage		80	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current – Continuous	(Note 1a)	4.7	A
	– Pulsed		20	
P <sub>D</sub>	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1.0	
		(Note 1c)	0.9	
Γ <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +175	°C
Therma	I Characteristics			
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Device Marking	Device	Reel Size	Tape width	Quantity
FDS3890	FDS3890	13"	12mm	2500 units

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**Electrical Characteristics**  $T_{A} = 25^{\circ}C$  unless otherwise noted Symbol Min Units Parameter **Test Conditions** Тур Max Drain-Source Avalanche Ratings (Note 2) W<sub>DSS</sub> Single Pulse Drain-Source  $V_{DD} = 40 \text{ V}, \text{ I}_{D} = 4.7 \text{ A}$ 175 mJ Avalanche Energy Maximum Drain-Source Avalanche  $I_{AR}$ 4.7 А Current **Off Characteristics**  $\mathsf{BV}_{\mathsf{DSS}}$ Drain-Source Breakdown Voltage  $V_{GS} = 0 V, I_D = 250 \mu A$ 80 V  $\Delta BV_{DSS}$ Breakdown Voltage Temperature  $I_D = 250 \ \mu A$ , Referenced to  $25^{\circ}C$ 86 mV/°C  $\Delta T_{\rm J}$ Coefficient Zero Gate Voltage Drain Current  $I_{\text{DSS}}$  $V_{DS} = 64 V_{.}$  $V_{GS} = 0 V$ 1 μA Gate-Body Leakage, Forward  $V_{GS} = 20 V$ ,  $V_{DS} = 0 V$ 100 nA IGSSF  $V_{GS} = -20 V$  $V_{DS} = 0 V$ I<sub>GSSR</sub> Gate-Body Leakage, Reverse -100 nA **On Characteristics** (Note 2) V V<sub>GS(th)</sub> Gate Threshold Voltage  $V_{DS} = V_{GS}, I_D = 250 \ \mu A$ 2 2.3 4 Gate Threshold Voltage  $I_D = 250 \ \mu A$ , Referenced to  $25^{\circ}C$  $\Delta V_{GS(th)}$ -6 mV/°C  $\Delta T_{J}$ **Temperature Coefficient** R<sub>DS(on)</sub> Static Drain-Source  $V_{GS} = 10 V.$  $I_{D} = 4.7 \text{ A}$ 34 44 mΩ **On-Resistance**  $V_{GS} = 6.0 V_{.}$  $I_{D} = 4.4 \text{ A}$ 37 50 V<sub>GS</sub> = 10 V, I<sub>D</sub> = 4.7 A, T<sub>J</sub> = 125°C 60 82 On-State Drain Current  $V_{GS} = 10 V$ ,  $V_{DS} = 5 V$ 20 А I<sub>D(on)</sub> s Forward Transconductance  $V_{DS} = 10 V$ ,  $I_{D} = 4.7 \text{ A}$ 24 **g**<sub>FS</sub> **Dynamic Characteristics** Input Capacitance 1180 pF  $C_{\text{iss}}$  $V_{DS} = 40 V$ ,  $V_{GS} = 0 V$ , Coss **Output Capacitance** f = 1.0 MHz 171 pF  $C_{\text{rss}}$ **Reverse Transfer Capacitance** 50 pF Switching Characteristics (Note 2) Turn-On Delay Time 11 20  $V_{DD} = 40 V$ ,  $I_{D} = 1 A$ , ns t<sub>d(on)</sub>  $V_{GS} = 10 V$ ,  $R_{GEN} = 6 \Omega$ Turn–On Rise Time 8 16 ns tr Turn-Off Delay Time 26 50 t<sub>d(off)</sub> ns Turn-Off Fall Time 12 25 tf ns Qq **Total Gate Charge**  $V_{DS} = 40 V$ ,  $I_{D} = 4.7 A$ , 25 35 nC  $V_{GS} = 10 V$ Q<sub>gs</sub> Gate-Source Charge 4.5 nC 5.8 nC  $Q_{qd}$ Gate-Drain Charge Drain–Source Diode Characteristics and Maximum Ratings Maximum Continuous Drain-Source Diode Forward Current  $I_{S}$ 1.3 А Drain–Source Diode Forward

Notes:

 $V_{\text{SD}}$ 

1. R<sub>0.A</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.

 $V_{GS} = 0 V$ ,  $I_{S} = 1.3 A$ 



Voltage

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%



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b) 125°C/W when mounted on a .04 in<sup>2</sup> pad of 2 oz copper

(Note 2)

c) 135°C/W when mounted on a minimum pad.

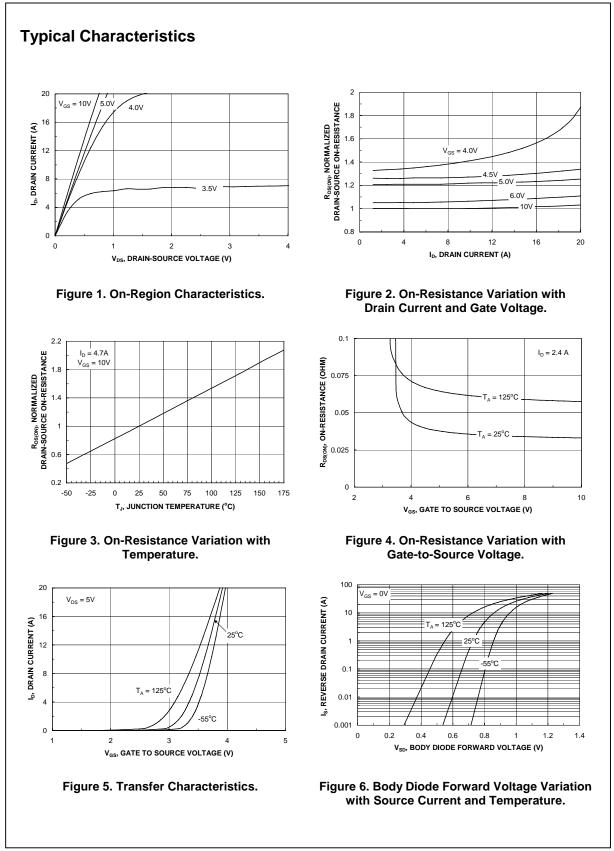
0.74

1.2

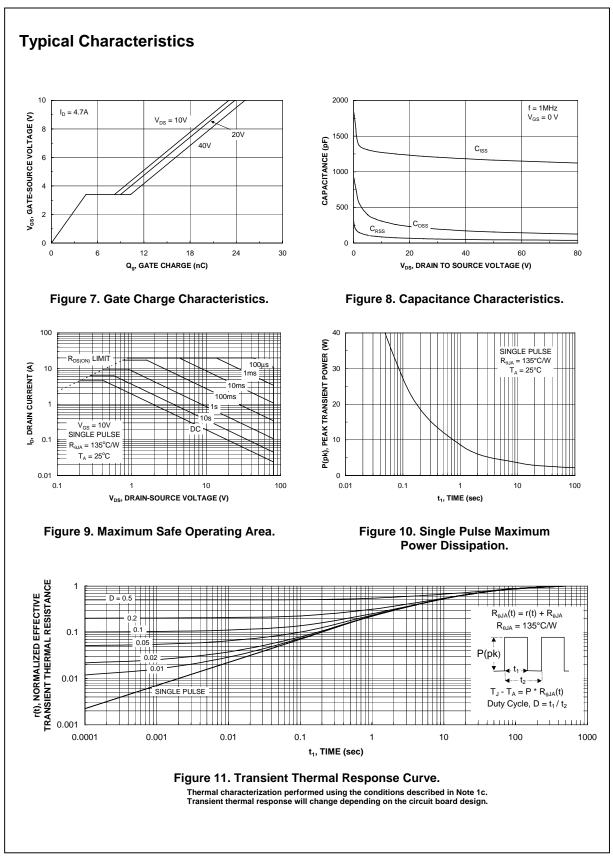
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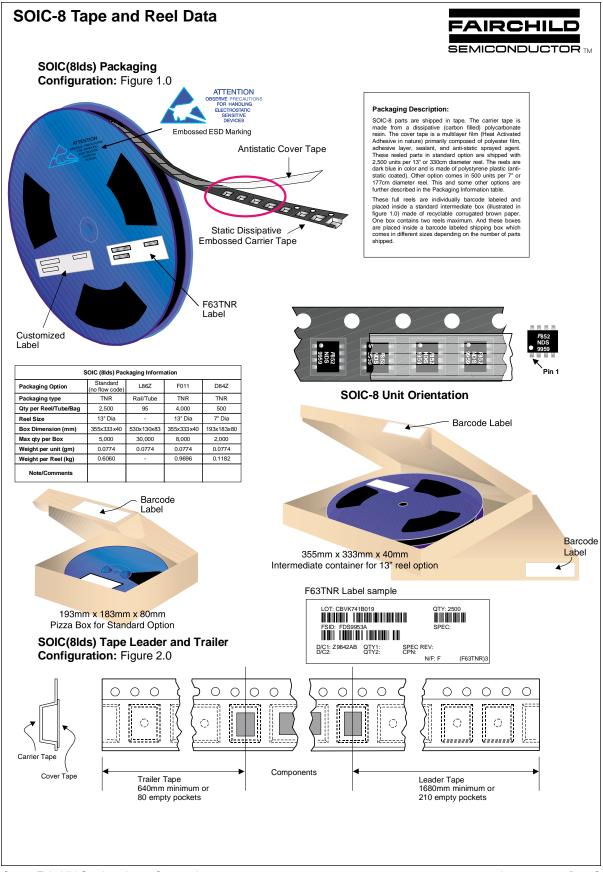
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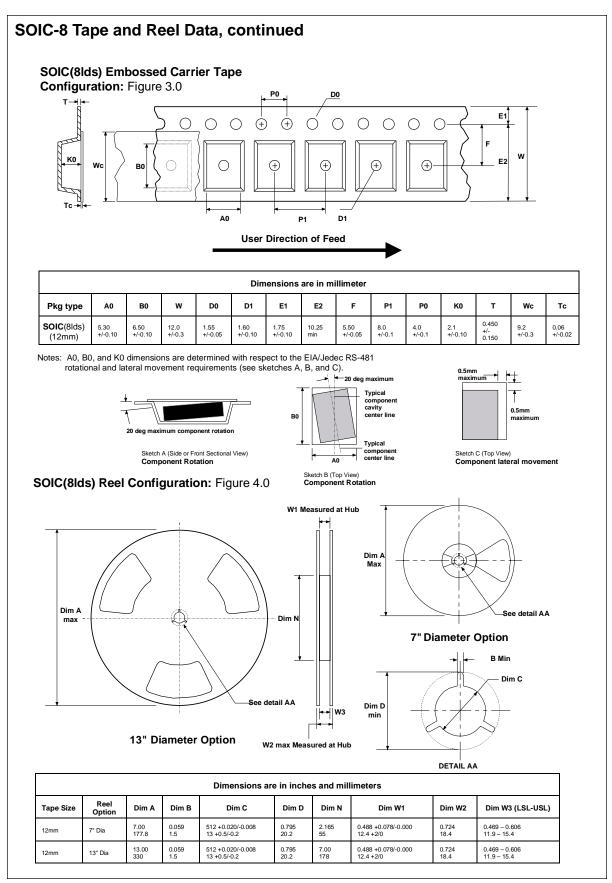


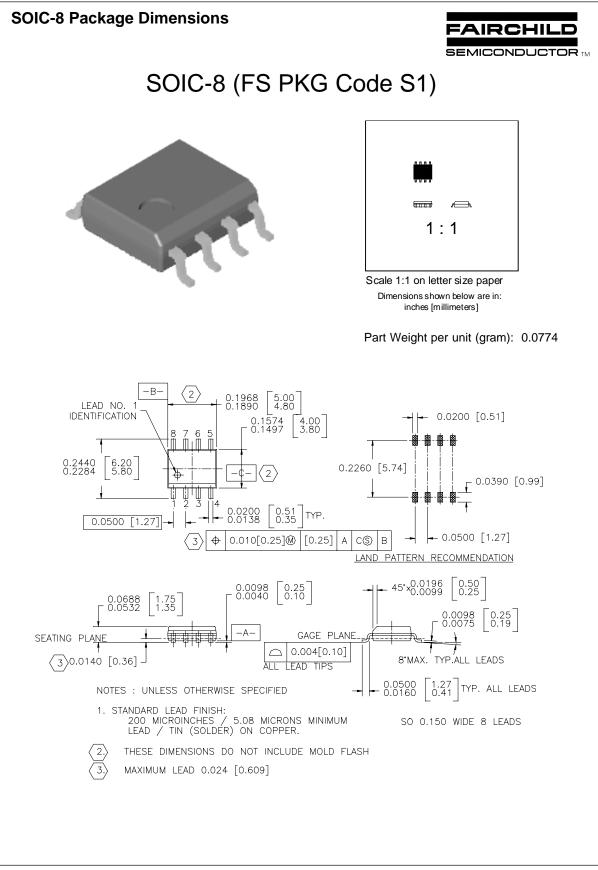
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